

# CCD40-11 AIMO Back Illuminated High Performance Sensor for Scientific Applications

# e2v technologies

#### **FEATURES**

- 1024 by 128 Pixel Format
- 26 μm Square Pixels
- Back Illuminated
- Image Area 26.6 x 3.3 mm
- Wide Dynamic Range
- Symmetrical Anti-static Gate Protection
- Advanced Inverted Mode Operation (AIMO)
- Anti-blooming Readout Register
- Zero Light Emitting Output Amplifier

#### **APPLICATIONS**

- Spectroscopy
- Scientific Imaging
- TDI Operation

#### INTRODUCTION

This version of the CCD40-11 is a high performance back illuminated CCD sensor designed for use in the scientific spectroscopy instrument market. With an array of 1024 x 128 26  $\mu m$  square pixels, it has an imaging area to suit spectrometer outputs of 26.6 x 3.3 mm (1.05 x 0.13 inch).

The readout register is organised along the long (1024 pixel) edge of the sensor and contains an anti-blooming drain to allow high speed binning operations of low level signals which may be adjacent to much stronger signals. The novel output amplifier design has no light emission.

Standard three phase clocking and buried channel charge transfer are employed and Advanced Inverted Mode Operation (AIMO) is included as standard. The AIMO format gives the same dark current suppression as with standard IMO devices whilst minimising the reduction in full-well capacity.

The CCD40-11 comes as standard with a broadband AR coating. Other coatings are available; contact e2v technologies for details.

The CCD40-11 is packaged in a 20-pin DIL ceramic package and is pin compatible (but not completely clock compatible) with the CCD30-11.



# **TYPICAL PERFORMANCE**

Pixel readout frequency	20 - 5000 kHz
Output amplifier responsivity	1.5 $\mu V/e^-$
Peak signal	500 ke <sup>-</sup> /pixel
Dynamic range	75 000:1
Readout noise (at 253 K, 20 kH	$1z) 6 e^{-rms}$
Peak output voltage	750 mV
Dark signal (at 293 K)	850 e <sup>-</sup> /pixel/s
Quantum efficiency (at 253 K, s	standard process,
broadband AR coating):	
350 nm	35 %
500 nm	90 %
650 nm	80 %
900 nm	40 %
Spectral range	200 - 1100 nm

## **GENERAL DATA**

#### **Format**

Image area								26.6 x 6.7	mm
Active pixels	(H)							1024	
	(∨)							. 128 (127 u	sable)
Pixel size .								26 x 26	μm
Number of o	utpu	t a	mp	lifi	ers			1	

#### **Package**

Package size						(	32.8	89	x 2	0.07	mm
Number of pins .											20
Inter-pin spacing										2.54	mm
Inter-row spacing									1	5.24	mm
Window material				qu	artz	0	r re	em	ova	ble (	glass

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# TYPICAL OPERATING CONDITIONS (See note 1)

		Typical
Ref.	Pin No.	Voltage
SS	5, 16	9.5 V
IØ1	4	12 V
IØ2	3	12 V
IØ3	2	12 V
RØ1	9	11 V
RØ2	8	11 V
RØ3	7	11 V
ØR	6	12 V
OG	12	3.5 V
OD	14	29 V
OS	13	see note 1
RD	15	17 V
DD	18	24 V
SG	19	0 V
NC	1, 10, 11, 20	

NC = Not connected SG = Spare gates

## **NOTES**

- 1. The value of this voltage is not critical and depends on the type and value of the load used. With a typical load of 2 to 5 mA, OS ia about 3 to 5 V below  $V_{\rm OD}$ .
- 2. Readout register clock pulse low levels + 1 V; other clock low levels 0  $\pm$  0.5 V.

## **BLEMISH SPECIFICATION**

GRADE	0	1	2
Column defects: black or slipped white	0 0	2 0	6 0
Black spots	9	18	80
Traps > 200 e-	1	2	5
White spots	15	30	50

Minimum separation between adjacent column defects is 50 pixels.

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